PTO/SB/08A (10-01)
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ļ				Application Number	Not assigned yet	
l	INFORMATION DIS	SCLOS	URE	Filing Date	On even date herewith	
İ	STATEMENT BY A	PPLICA	ANT	First Named Inventor	J. YUGAMI, et al.	
				Art Unit	Not assigned yet	
	(use as many sheets a	necessa	n/)	Examiner Name	Not assigned yet	
Sheet	1	of	1	Attorney Docket Number	520.40885VX1	

U.S. PATENT DOCUMENTS						
Examiner Initials'	Cite No.1	Document Number  Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
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3136		5.514.891	05-1996	Abrokwah et al.		
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FOREIGN PATENT DOCUMENTS							
Examiner	Cite	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Τ°	
Initials'	No.	Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>6</sup> (if known)					
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OTHER PRIOR ART—NON PATENT LITERATURE DOCUMENTS					
Initials* No. item (book, magazine, journal, serial, symposium, catalog, etc.), date, pa		Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), authlieber, other country where published.	T²		
500		1998 International Electron Electron Device Meeting Technical Digest, (Pgs. 1038-1040), A 1.1 nm Oxide Equivalent Gate Insulator Formed Using TiO2 on Nitrided Silicon.			
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Examiner	1.016	Date	7.20 011
Signature	AND D. BY	Considered	7.20.09

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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